

Table of Contents

ix *List of Contributors*

INTRODUCTION

- 3 **Technology of proximal probe lithography: an overview**
J. A. Dagata, National Institute of Standards and Technology;
C. R. K. Marrian, Naval Research Lab.

PART I. NANOLITHOGRAPHY

- 16 **Principles and techniques of STM lithography**
M. A. McCord, IBM Corp.; R. F. W. Pease, Stanford Univ.
- 33 **Role of scanning probe microscopes in the development of nanoelectric devices**
A. Majumdar, S. M. Lindsay, Arizona State Univ.
- 58 **Low voltage e-beam lithography with the STM**
C. R. K. Marrian, E. A. Dobisz, Naval Research Lab.; J. A. Dagata, National Institute of Standards and Technology
- 74 **Nanolithography and atomic manipulation on silicon surfaces by STM**
F. Grey, A. Kobayashi, H. Uchida, D. H. Huang, M. Aono, Aono Atomcraft Project (Japan)
- 100 **Scanning tunneling microscope-based fabrication and characterization on passivated semiconductor surfaces**
J. A. Dagata, J. Schneir, National Institute of Standards and Technology
- 111 **Scanning tunneling microscope-based nanolithography for electronic device fabrication**
J. W. Lyding, R. T. Brockenbrough, P. Fay, J. R. Tucker, K. Hess, Univ. of Illinois; T. K. Higman, Univ. of Minnesota
- 127 **Arrayed lithography using STM-based microcolumns**
T. H. P. Chang, IBM T.J. Watson Research Ctr.; L. P. Muray, Cornell Univ.; U. Staufer, Univ. of Basel (Switzerland); M. A. McCord, D. P. Kern, IBM T.J. Watson Research Ctr.

PART II. FABRICATION

- 162 **Nanofabrication by scanning probe instruments: methods, potential applications, and key issues**
R. Wiesendanger, Univ. of Basel (Switzerland)
- 188 **Direct writing of metallic nanostructures with the scanning tunneling microscope**
A. L. de Lozanne, W. F. Smith, E. E. Ehrichs, Univ. of Texas/Austin

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- 200 **Fabrication of nanometer-scale structures**
M. H. Nayfeh, Univ. of Illinois/Urbana-Champaign
- 218 **Modification and manipulation of layered materials using scanned probe microscopies**
C. M. Lieber, Harvard Univ.
- 234 **Atomic force microscopy experimentation at surfaces: hardness, wear, and lithographic applications**
T. A. Jung, Univ. of Basel (Switzerland) and Paul Scherrer Institute (Switzerland); A. Moser, Univ. of Basel (Switzerland); M. T. Gale, Paul Scherrer Institute (Switzerland); H. J. Hug, U. D. Schwarz, Univ. of Basel (Switzerland)
- 268 **Fabrication and characterization using scanned nanoprobe**
G. C. Wetsel Jr., S. E. McBride, H. M. Marchman, Univ. of Texas/Dallas
- 289 **Ballistic electron emission microscopy: from electron transport physics to nanoscale materials science**
H. D. Hallen, AT&T Bell Labs.

PART III. METROLOGY

- 322 **Generating and measuring displacements up to 0.1 m to an accuracy of 0.1 nm: Is it possible?**
E. C. Teague, National Institute of Standards and Technology
- 364 **Metrology with scanning probe microscopes**
J. E. Griffith, AT&T Bell Labs.; D. A. Grigg, Digital Instruments;
G. P. Kochanski, M. J. Vasile, AT&T Bell Labs.; P. E. Russell, North Carolina State Univ.
- 390 **Metrology applications of scanning probe microscopes**
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